



LT-150 Manual Probe Station

RF • Microwave Measurement Solution

T Plus Co. Ltd.

■ Specification / LT-150

Chuck Stage

Parameter		Unit	Adjustable Range				Note
			X	Y	Z	θ	
Travel	Rough Stage	mm	± 80	± 80	-	-	•Free Moving Handle
	Fine Stage	mm	11	11	10	10°	•Micrometer Head
	Chuck Roll Out	mm	-	>200	-	-	-
Parameter		Unit	Min		Typical		Max
Planarity (chuck to Platen)		um			<10 (TBD)		
Main Chuck	Chucking Method		Vacuum Chuck / Flat, hole type				
	Size	mm	$\Phi 150$ / applicable 4 and 6inch wafer				
	Surface Planarity	um	TBD				
	Material		TBD (Stainless Steel)				
Sub Chuck (Option)	Chucking Method		Vacuum Chuck / Flat, hole type				
	Size	mm	$\square 30$ (1 or 2 chucks)				

Physical Dimensions

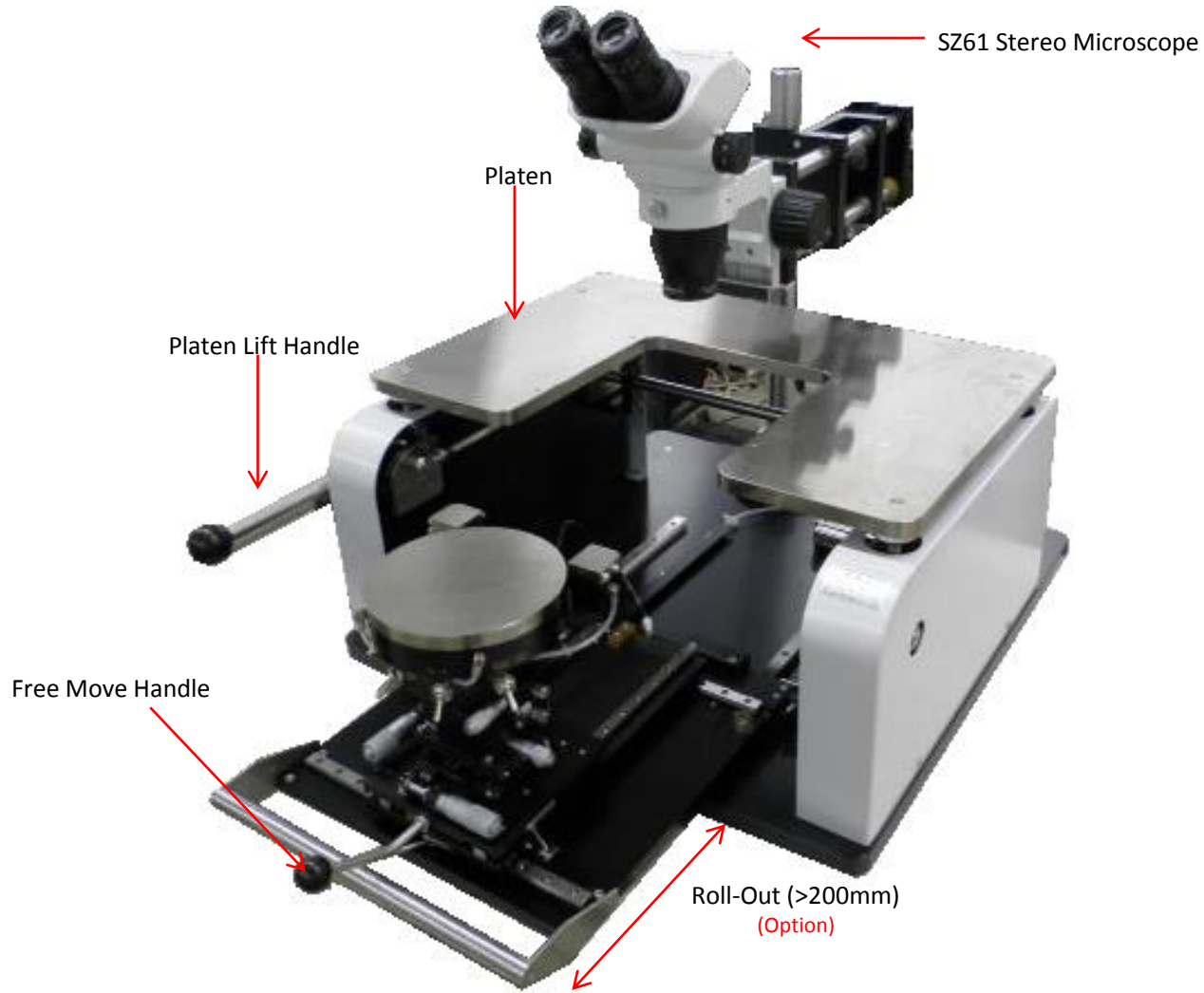
Parameter	Unit	W	D	H	Note
Dimensions	mm	600	600	320	•w/o microscope stand
Wight	Kg	60			

Platen Lift

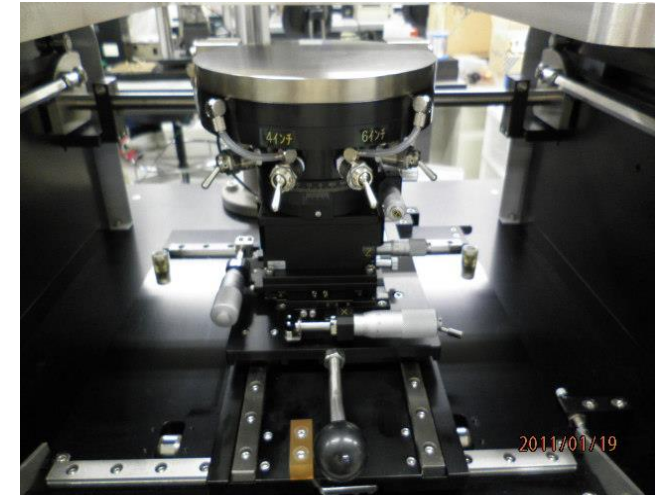
Parameter	Unit	Low	Mid	High	Note
Platen Lift	mm	0	<0.5	10	•3-Crick Position (low, mid, Hi)



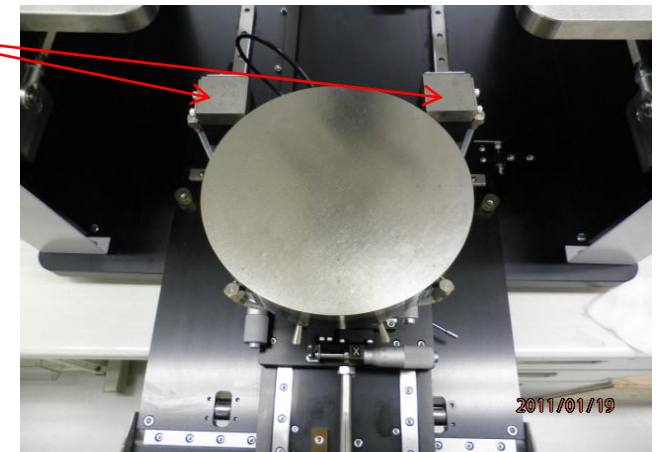
Visual



Wafer Chuck (should be custom for chip, and module)



Sub Chuck (Option)



■Probe Positioner (standard)

Standard RF/DC probe positioner "MP series)

Parameter	Unit	Adjustable Range				Note
		X	Y	Z	Rolling	
Travel	mm	±7.5	±7.5	10		•Micrometer Head / Min scale is 10um
Axis		Standard			Option	



■Microscope (standard)

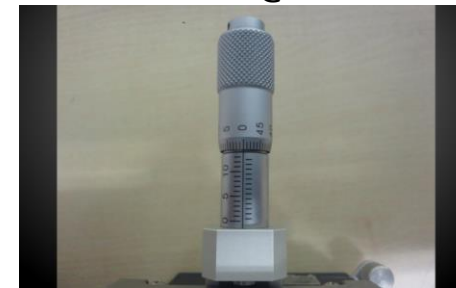
Olympus Stereo Microscope SZ61 (Maximum Magnification x45)

Parameter	Unit	Magnification		Q'ty	Brand
		Min	Max		
SZ61 Stereo Microscope	x	0.65	4.5	1	•Olympus
Eye Piece	x	-	10	1set	
Focus Mount		-	-	1	
LED ring light		-	-	1	

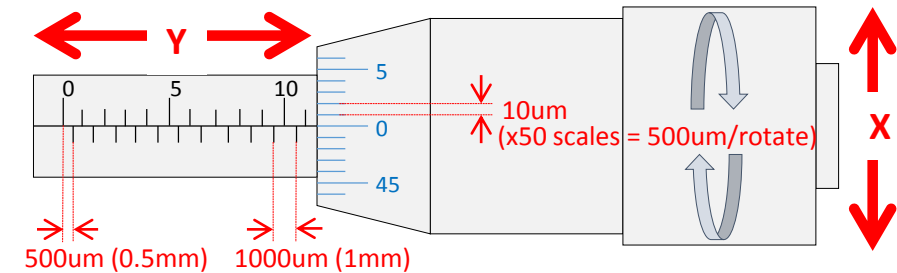
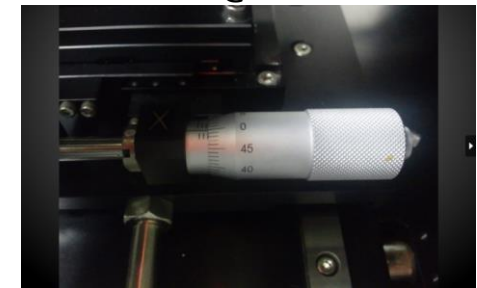
■Micrometer Accuracy (standard)

Parameter	Unit	Scale Size		Note	
		X	Y		
Minimum Scale	Probe Station	um	10	500/1000	•1 rotate cycle: 500um travel
	Positionar	um	10	500/1000	•1 rotate cycle: 500um travel

Micrometer@Potionar



Micrometer@Probe Station



T Plus Co. Ltd.

3-3-69 Misaki, Funabashi, Chiba, 274-0812

Contact: Toshi Ohi

Email: toshi-ohi@tplus-co.com

(World Wide Contact)